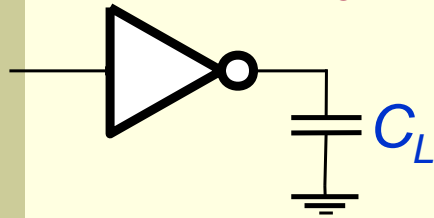


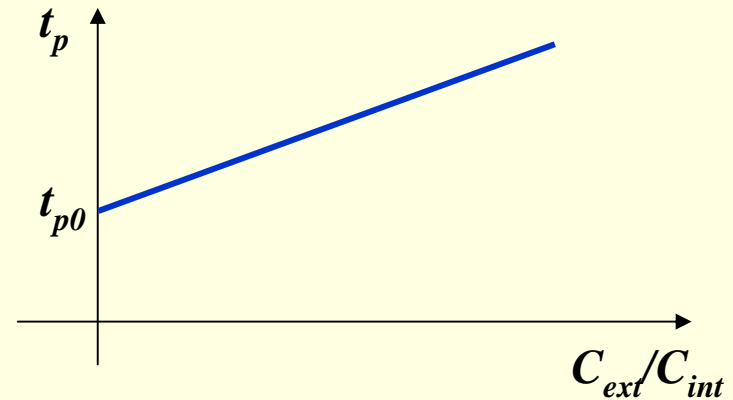
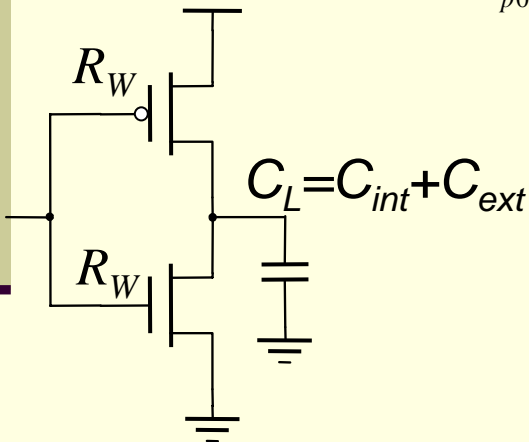
# Dynamic operation – 20

## A simple model for the propagation delay

- Symmetric inverter (rise and fall delays are identical)
- Total capacitance is linear
- Minimum length devices



$$t_p = 0.69R_W C_L =$$
$$0.69R_W C_{int} (1 + C_{ext} / C_{int}) =$$
$$t_{p0} (1 + C_{ext} / C_{int})$$



Propagation delay vs.  $C_{ext}/C_{int}$  ratio

1.  $t_{p0}$  (for minimum-L devices) is independent of the sizing (W's) of the gate;
2. Making W infinitely large eliminates the impact of any external load

$C_{int}$  – intrinsic (self-loading) output capacitance

$C_{ext}$  – extrinsic load capacitance (fan-out + wiring)

# Dynamic operation – 21

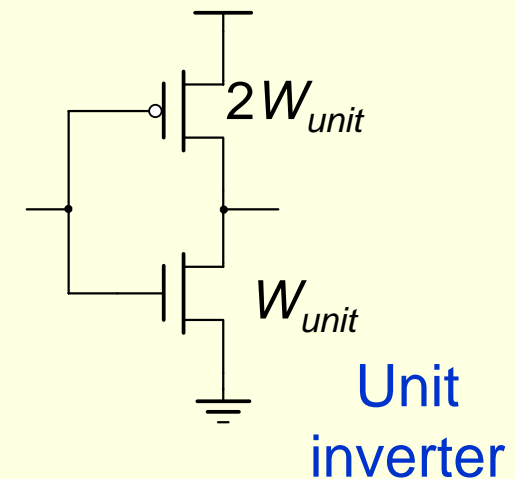
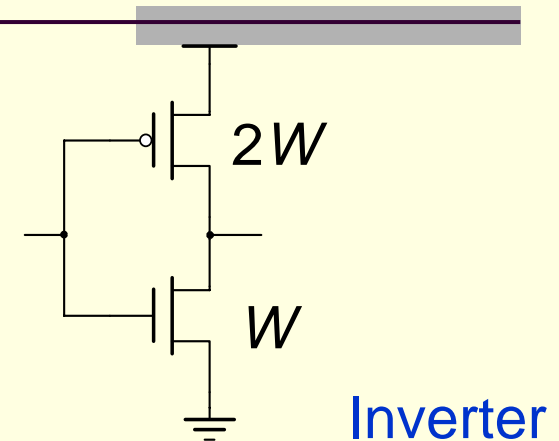
## Inverter Delay

- Minimum length devices
- Assume that for  $W_P = 2W_N = 2W$ 
  - same pull-up and pull-down currents
  - approx. equal resistances  $R_N = R_P$
  - approx. equal rise  $t_{pLH}$  and fall  $t_{pHL}$  delays
- Analyze as an RC network

$$R_P = R_{unit} \left( \frac{W_P}{W_{unit}} \right)^{-1} \approx R_{unit} \left( \frac{W_N}{W_{unit}} \right)^{-1} = R_N = R_W$$

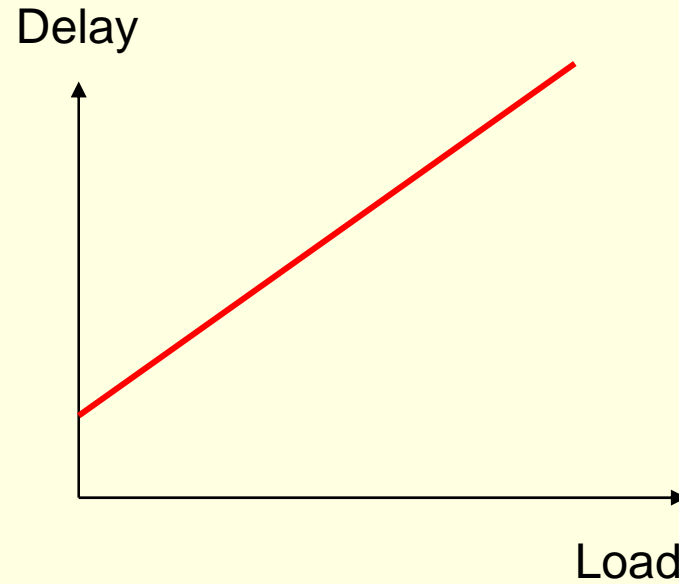
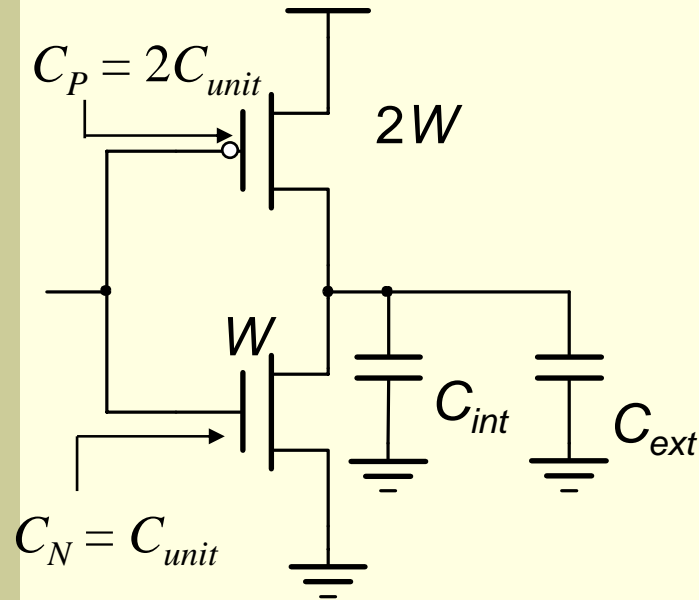
$$\text{Delay (D): } t_{pHL} = (\ln 2) R_N C_L \quad t_{pLH} = (\ln 2) R_P C_L$$

$$\text{Load for previous stage: } C_{gin} = 3 \frac{W}{W_{unit}} C_{unit}$$



# Dynamic operation – 22

## Inverter Delay



$$\begin{aligned} \text{Delay} &= 0.69R_W(C_{int} + C_{ext}) = 0.69R_W C_{int} + 0.69R_W C_{ext} \\ &= 0.69R_W C_{int}(1 + C_{ext}/C_{int}) \\ &= \text{Delay (Internal)} + \text{Delay (Load)} \end{aligned}$$

Note:  
 $R_W \propto L/W$   
 $C_{int} \propto WL$

# Dynamic operation – 23

## Delay Formula

$$\text{Delay} \sim R_W (C_{int} + C_{ext})$$

$$t_p = kR_W C_{int} (1 + C_{ext}/C_{int}) = t_{p0} (1 + f/\gamma)$$

$$\begin{aligned} C_{int} &= \gamma C_{gin} \text{ with } \gamma \approx 1 \\ f &= C_{ext}/C_{gin} \text{ - effective fanout} \\ R &= R_{unit}/W; C_{int} = WC_{unit} \\ t_{p0} &= 0.69R_{unit}C_{unit} \end{aligned}$$

Note:

$$R_W \propto L/W$$

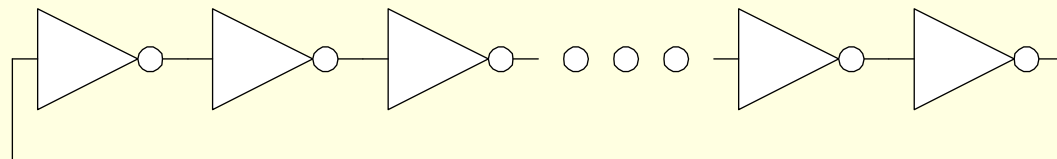
$$C_{int} \propto WL$$

$t_{p0} \propto L^2 \rightarrow$  minimum L for minimum delay

# Dynamic operation – 24

## Ring oscillators - 1

N: (odd) number of inverters (usually >5)



$$t_p = kR_W C_{int} \left(1 + C_{ext} / C_{int}\right) = t_{p0} \left(1 + f / \gamma\right)$$

$$C_{int} = \gamma C_{gin} \text{ with } \gamma \approx 1$$
$$f = C_{ext} / C_{gin} = 1$$

$$f_{osc} = \frac{1}{2Nt_p} \rightarrow t_p = \frac{1}{2Nf_{osc}}$$

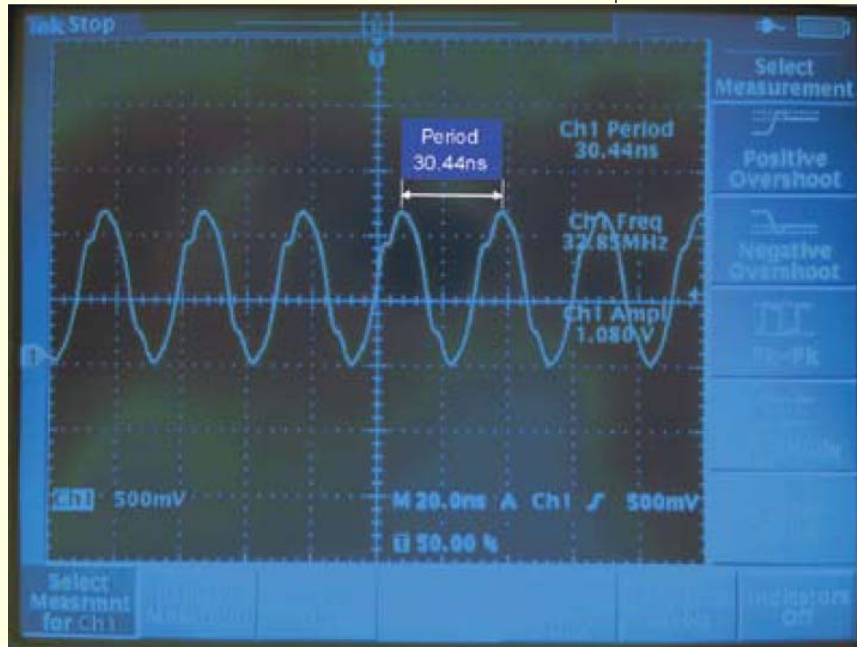
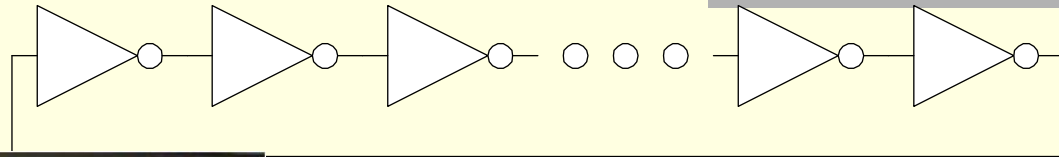
Ring oscillators are used as process monitors to verify if a chip is faster or slower than nominally expected.

Ex: 31-stage ring oscillator in a 180 nm process oscillates at 540 MHz.

# Dynamic operation – 25

## Ring oscillators - 2

N: (odd) number of inverters (usually >5)



$V_{DD}$	0.8V	1.0V	1.2V
Frequency	17.2MHz	26.3MHz	33.4MHz

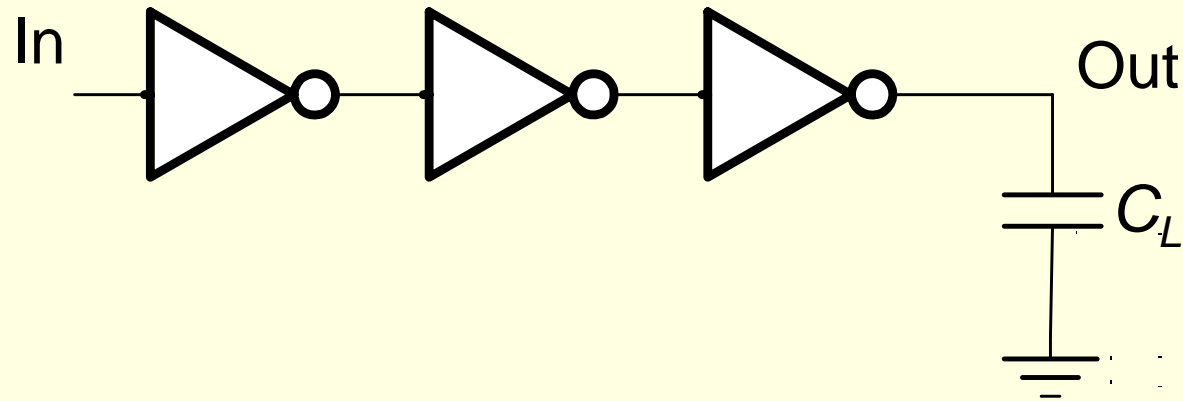
Ring oscillator output as viewed with an oscilloscope. The time base is set to 20ns per division and the voltage scale is set to 500mV per division. The measured wave period is 30.44ns and the measured amplitude is 1.08V when the supply voltage is 1.2V.

Source:  
[www.keithley.com.cn/data?asset=51070](http://www.keithley.com.cn/data?asset=51070)

EEL7312 – INE5442  
Digital Integrated Circuits

# Dynamic operation – 26

## Inverter chain - 1



If  $C_L$  is given:

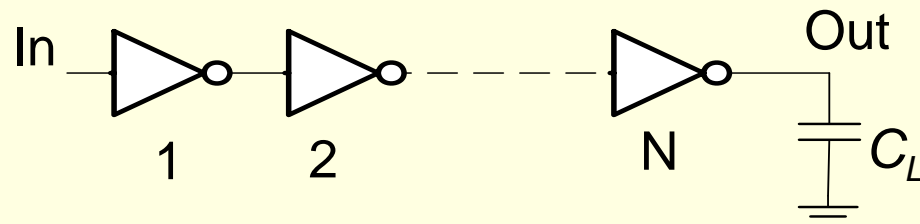
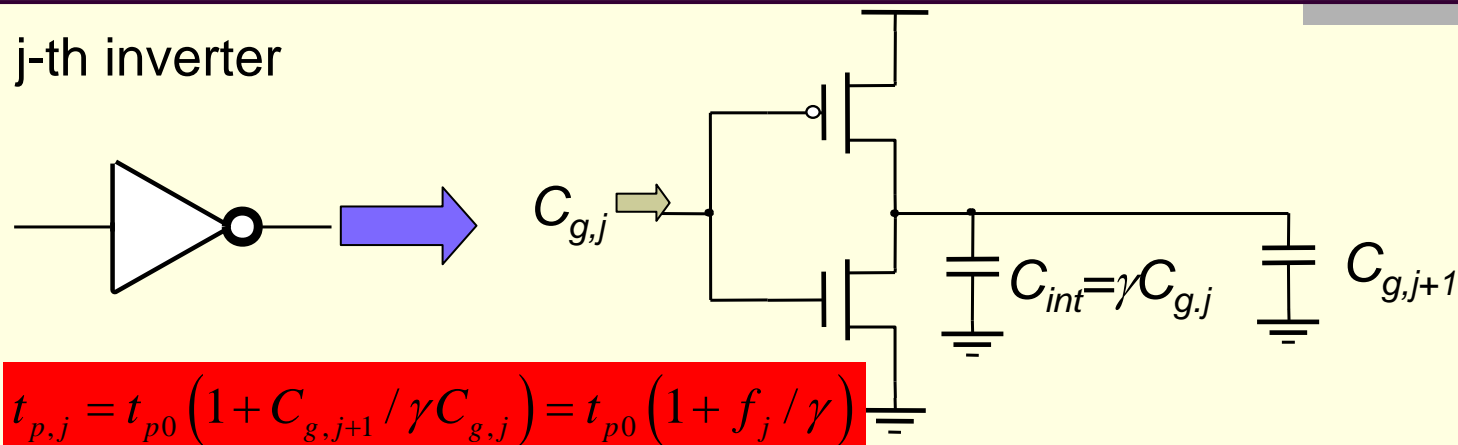
- How many stages are needed to minimize the delay?
- How to size the inverters?

May need some additional constraints.

# Dynamic operation – 27

## Inverter chain - 2

j-th inverter



$$t_p = \sum_{j=1}^N t_{p,j} = t_{p0} \sum_{j=1}^N \left(1 + C_{g,j+1} / \gamma C_{g,j}\right); \quad C_{g,N+1} = C_L \quad \rightarrow \quad N-1 \text{ unknowns: } C_{g,2}, C_{g,3}, \dots, C_{g,N-1}, C_{g,N}$$

*First inverter is minimally sized*

Source: Rabaey



# Dynamic operation – 28

## Inverter chain - 3

Let's minimize  $t_p = \sum_{j=1}^N t_{p,j} = t_{p0} \sum_{j=1}^N (1 + C_{g,j+1} / \gamma C_{g,j}); C_{g,N+1} = C_L$

Taking the  $N-1$  derivatives partial derivatives and equating them to 0 we find that  $C_{g,j} = \sqrt{C_{g,j-1} C_{g,j+1}}$

Thus, each inverter is sized up by the same factor  $f$  wrt the preceding gate

$$f = C_{g,j+1} / C_{g,j} = \sqrt[N]{C_L / C_{g,1}} = \sqrt[N]{F}$$

The minimum delay is

$$t_p = t_{p0} \sum_{j=1}^N (1 + f / \gamma) = N t_{p0} (1 + \sqrt[N]{F} / \gamma) \rightarrow \text{What's } N \text{ that minimizes delay?}$$

# Dynamic operation – 29

## Inverter chain - 4

$$t_p = t_{p0} \sum_{j=1}^N (1 + f / \gamma) = N t_{p0} \left( 1 + \sqrt[N]{F} / \gamma \right) \quad \longrightarrow \quad dt_p/dN=0$$

The minimum delay is  
for  $N$  obtained from  
or, equivalently

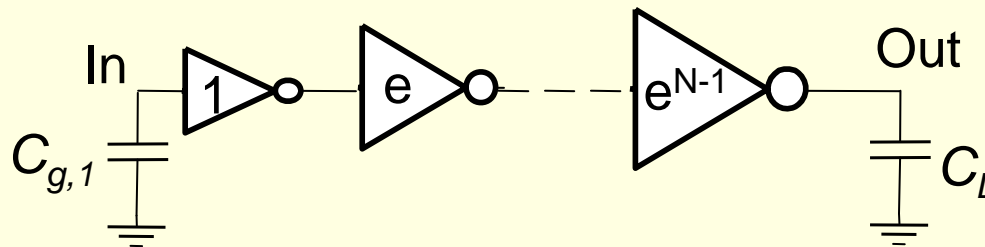
$$\gamma + \sqrt[N]{F} (1 - \ln F / N) = 0$$

$$f = e^{(1 + \gamma / f)}$$

Canonical case:  $\gamma = 0$

$$\left. \begin{array}{l} f = e, \quad N = \ln F = \ln(C_L / C_{g,1}) \\ t_p = e t_{pi} \ln(C_L / C_{g,1}) \end{array} \right\}$$

$t_{pi}$ : propagation delay of  
unit inverter loaded with  
another unit inverter

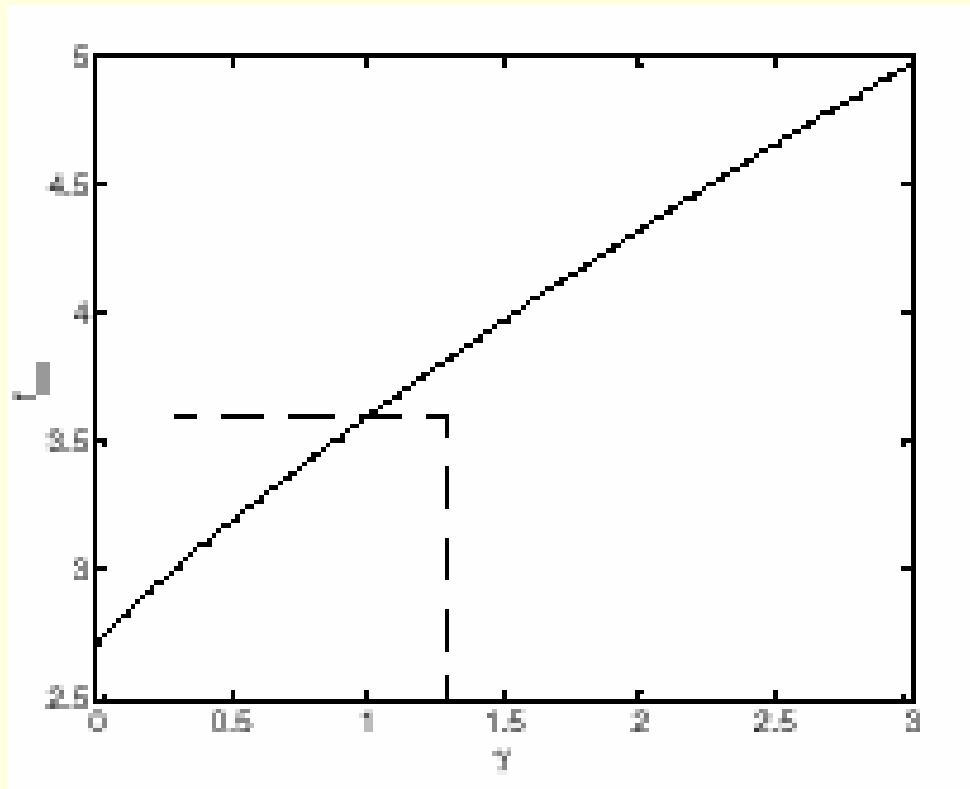


Source: Rabaey

# Dynamic operation – 30

## Inverter chain - 5

Optimum effective fan-out  $f$        $f = \exp(1 + \gamma/f)$



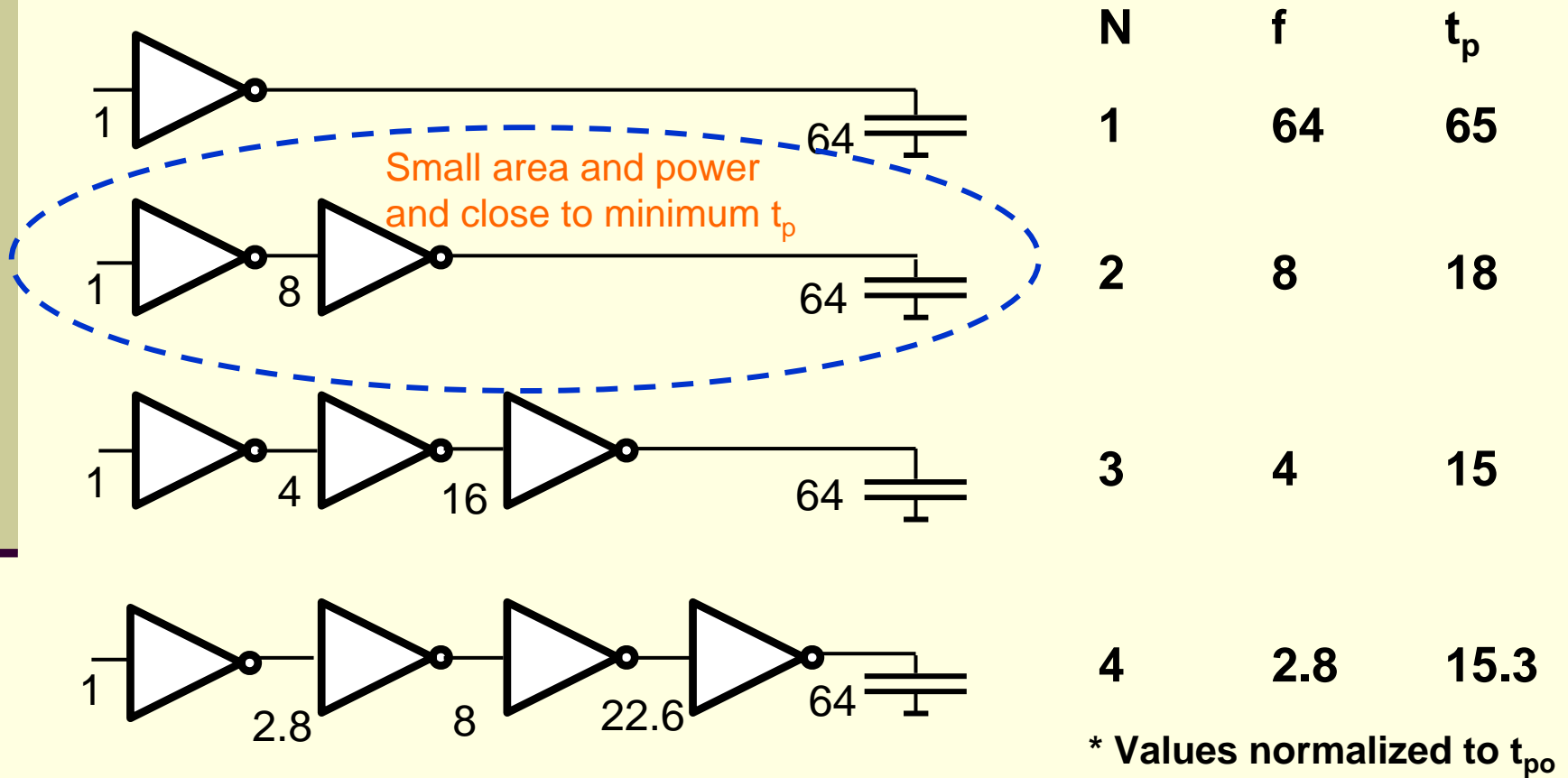
$f_{opt} = 3.6$   
for  $\gamma=1$

Source: Rabaey

# Dynamic operation – 31

## Inverter chain - 6

### Buffer Design



Sources: Weste and Rabaey

# Power, energy, and energy delay – 1

- Power is drawn from a voltage source attached to the  $V_{DD}$  pin(s) of a chip.

- Instantaneous Power:  $p(t) = i(t)v(t)$   
**Delivered by the power source**  $p(t) = i_{DD}(t)V_{DD}$

- Energy: 
$$E = \int_0^T p(t)dt = \int_0^T i(t)v(t)dt$$

- Average Power: 
$$P_{\text{avg}} = \frac{E}{T} = \frac{1}{T} \int_0^T i(t)v(t)dt$$

# Power, energy, and energy delay – 2

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## Where Does Power Go in CMOS?

- **Dynamic Power Consumption**

Charging and Discharging Capacitors

- **Short Circuit Currents**

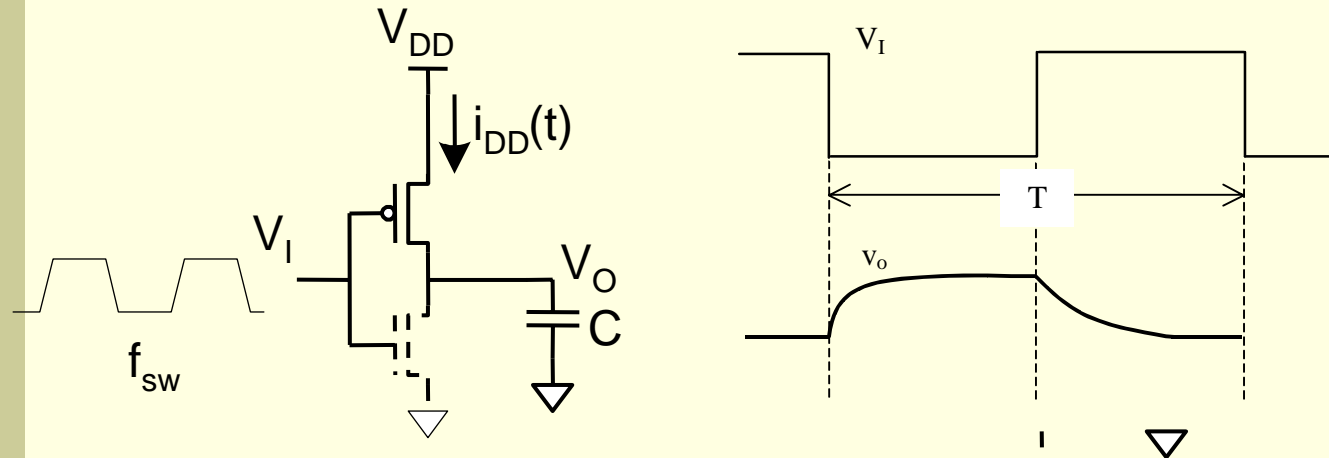
Short Circuit Path between Supply Rails during Switching

- **Leakage**

Leaking diodes and transistors

# Power, energy, and energy delay – 3

## Dynamic Power Dissipation



**Energy delivered by the power supply ( $E_{DD}$ ) to charge  $C$**

$$E_{DD} = \int_0^T i_{DD}(t) V_{DD} dt = V_{DD} \int_0^T i_{DD}(t) dt = V_{DD} \int_0^{V_{DD}} C dv_o = CV_{DD}^2$$

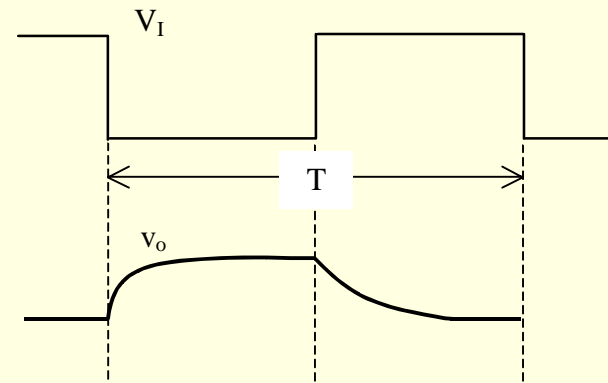
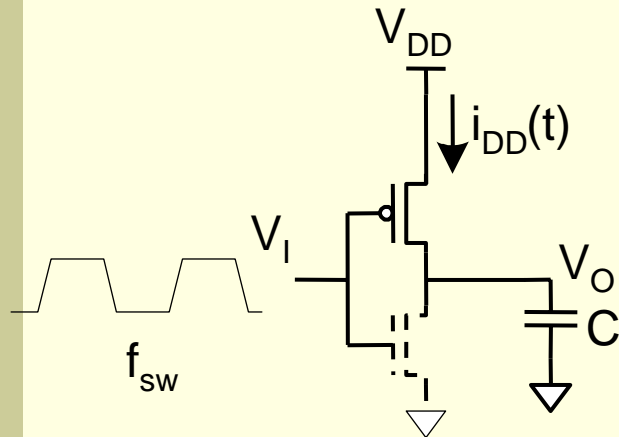
**The energy stored in the fully charged capacitor is**

$$E_C = \int_0^T v_o i_C dt = \int_0^{V_{DD}} v_o C dv_o = C \frac{V_{DD}^2}{2}$$

**Where's the other half of the energy delivered by  $V_{DD}$ ?**

# Power, energy, and energy delay – 4

## Dynamic Power Dissipation



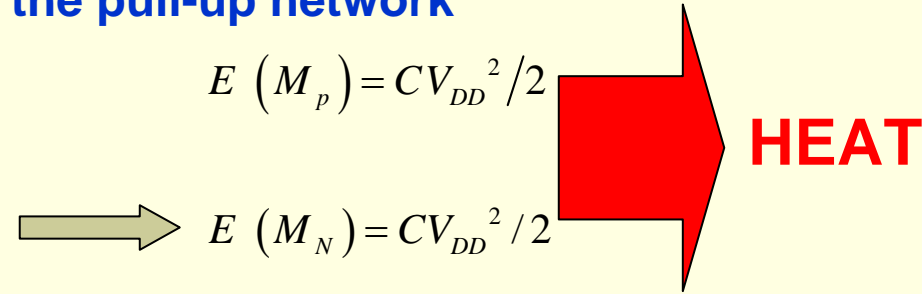
Where's the energy delivered by  $V_{DD}$ ?

One half of the energy is stored in C whereas the other half is converted into heat in the pull-up network

During the 1  $\rightarrow$  0 transition of the output, the energy stored on C is dissipated into the n-channel transistor

$$E (M_p) = CV_{DD}^2 / 2$$

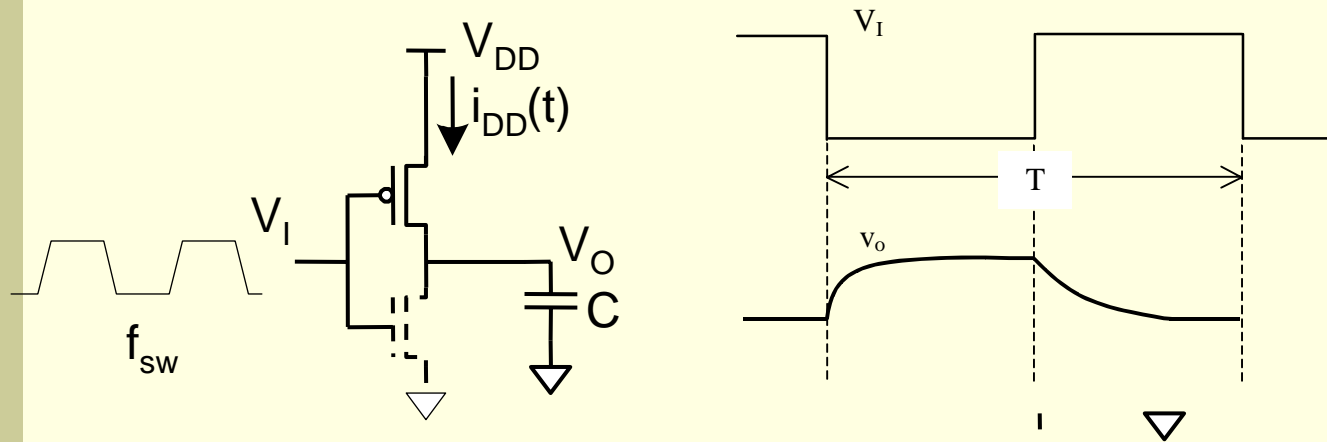
$$E (M_n) = CV_{DD}^2 / 2$$





# Power, energy, and energy delay – 5

## Dynamic Power Dissipation



$$P_{\text{dynamic}} = \frac{1}{T} \int_0^T i_{DD}(t) V_{DD} dt = \frac{V_{DD}}{T} \int_0^T i_{DD}(t) dt$$

$$= \frac{V_{DD}}{T} [T f_{sw} C V_{DD}] = C V_{DD}^2 f_{sw}$$

clock frequency =  $f_{ck}$

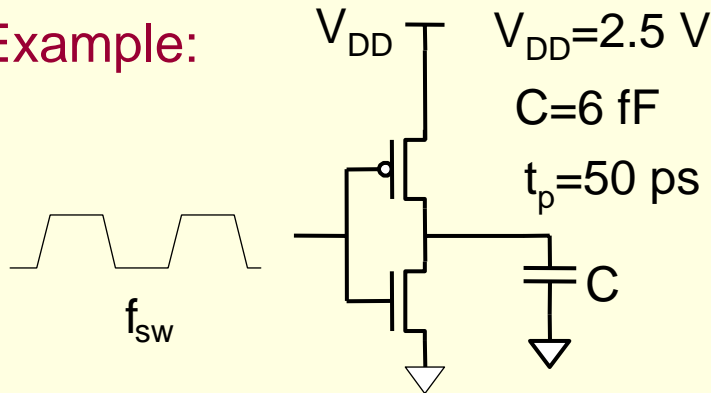
$f_{sw} = \alpha f_{ck}$ ,  $\alpha \rightarrow$  activity factor

**For low power reduce  $C$ ,  $V_{DD}$ , and  $f_{sw}$**

# Power, energy, and energy delay – 6

## Dynamic Power Dissipation

Example:



Energy delivered by the power supply ( $E_{DD}$ ) to charge  $C$

$$E_{DD} = CV_{DD}^2 = 6 \cdot 2.5^2 = 37.5 \text{ fJ}$$

Assume that  $f_{ck} = 1/4t_p = 5 \text{ GHz}$

For  $f_{sw} = f_{ck} = 5 \text{ GHz}$ , the average dynamic power dissipation is

$$P_{\text{dynamic}} = CV_{DD}^2 f_{sw} = 37.5 \cdot 5 \text{ fJ} \cdot \text{GHz} = 187.5 \text{ } \mu\text{W}$$

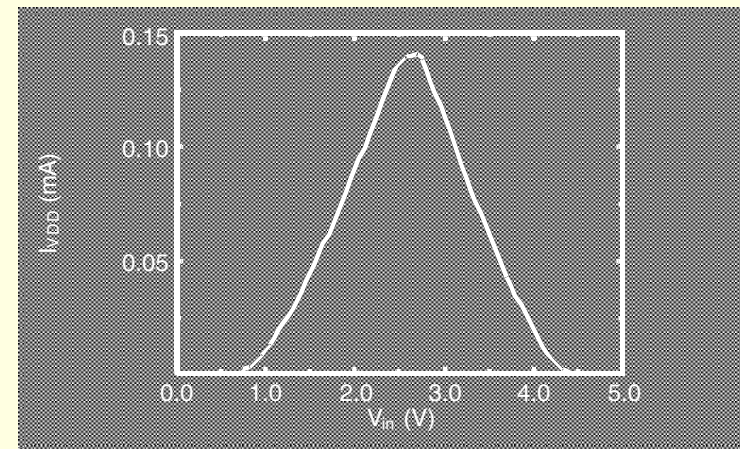
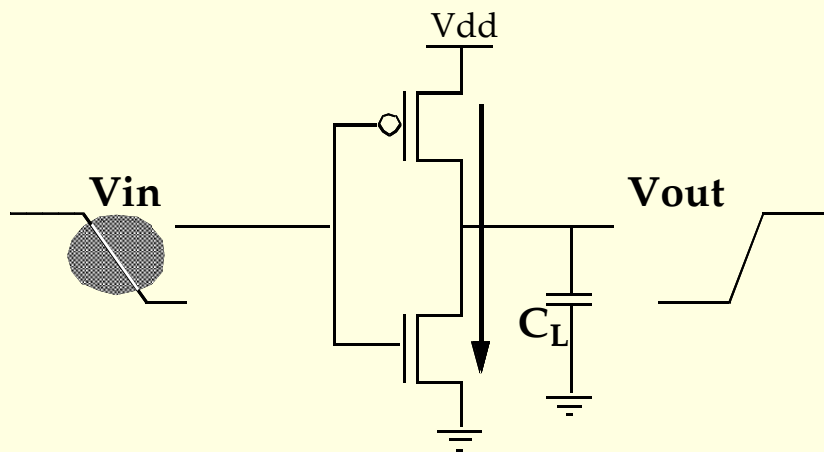
For an activity factor of 0.1, the average dynamic power dissipation is  $\sim 18 \text{ } \mu\text{W}$

**One million identical inverters with the same activity factor of 0.1 would give a total power dissipation of  $\sim 18 \text{ W}$**

# Power, energy, and energy delay – 7

## Short Circuit Currents

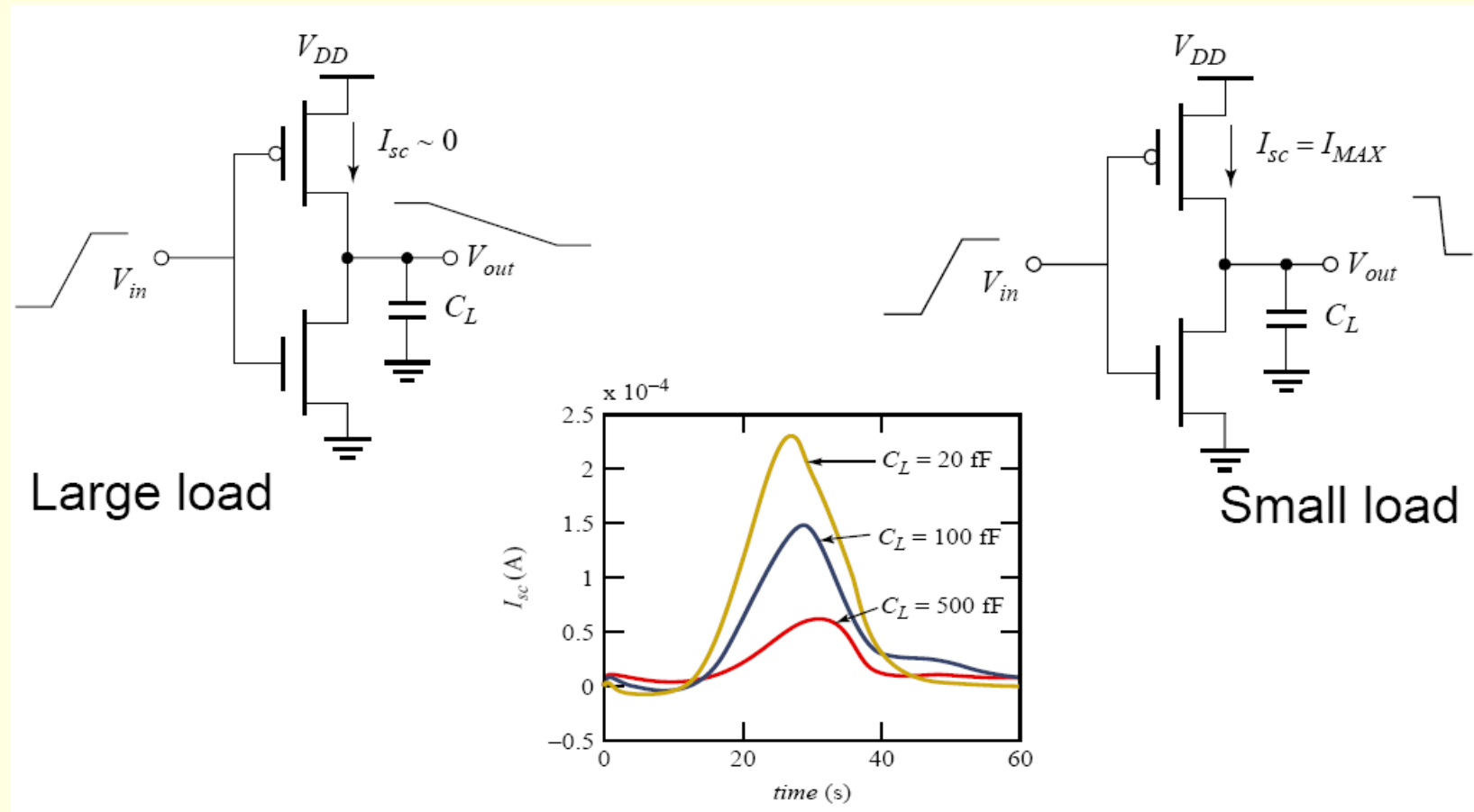
- When transistors switch, both nMOS and pMOS transistors may be momentarily ON at once
- Typically < 10% of dynamic power if rise/fall times are comparable for input and output



Source: Rabaey

# Power, energy, and energy delay – 8

## Short Circuit Currents

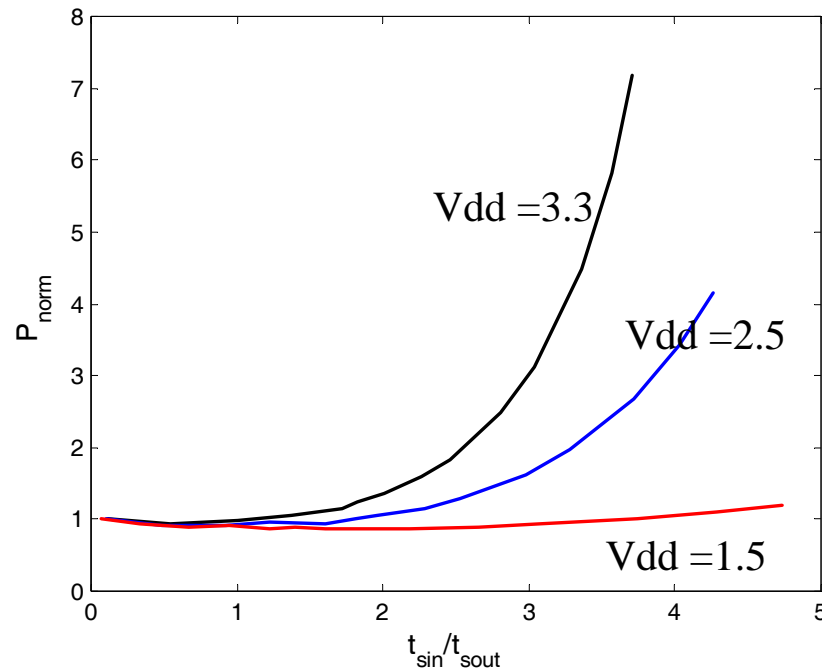


Source: Rabaey

# Power, energy, and energy delay – 9

## Short Circuit Currents

### *Minimizing Short-Circuit Power*

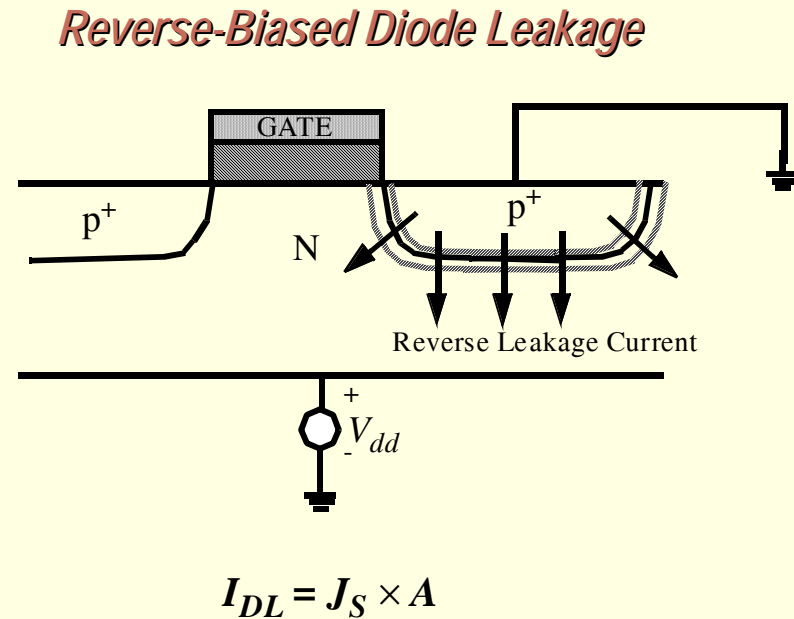
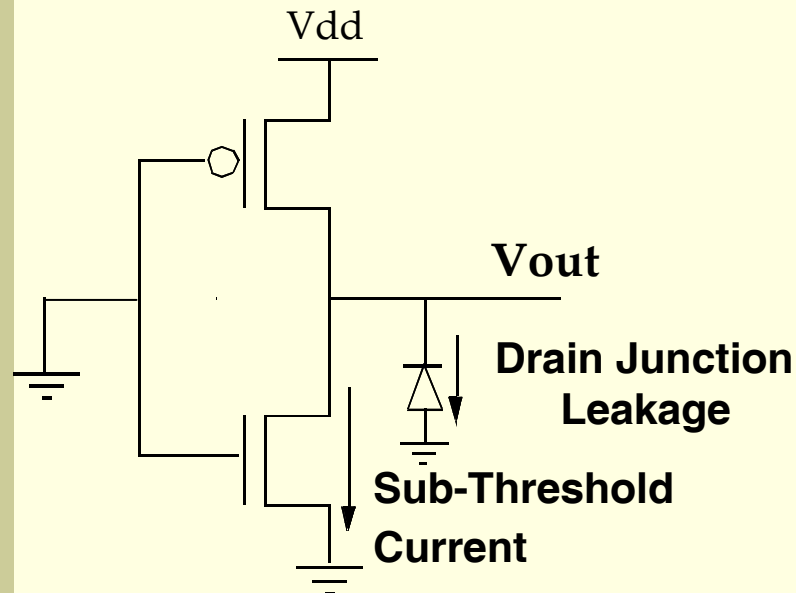


- Keep the input and output rise/fall times the same (< 10% of Total Consumption)  
from [Veendrick84]  
(*IEEE Journal of Solid-State Circuits*, August 1984)
- If  $V_{dd} < V_{tn} + |V_{tp}|$  then short-circuit power can be *eliminated!*

Source: Rabaey

# Power, energy, and energy delay – 10

## Leakage → static dissipation

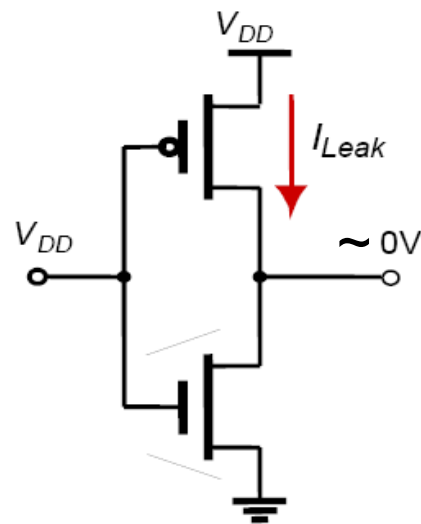


Sub-threshold current one of most compelling issues in low-energy circuit design!

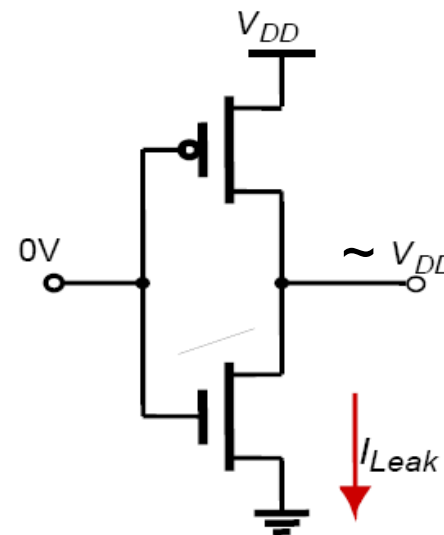
# Power, energy, and energy delay – 11

## Leakage → static dissipation

Transistors that are supposed to be off - leak



Input at  $V_{DD}$

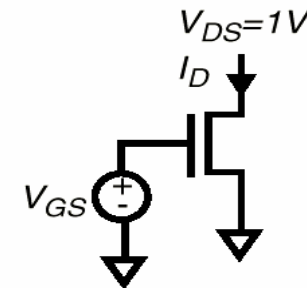
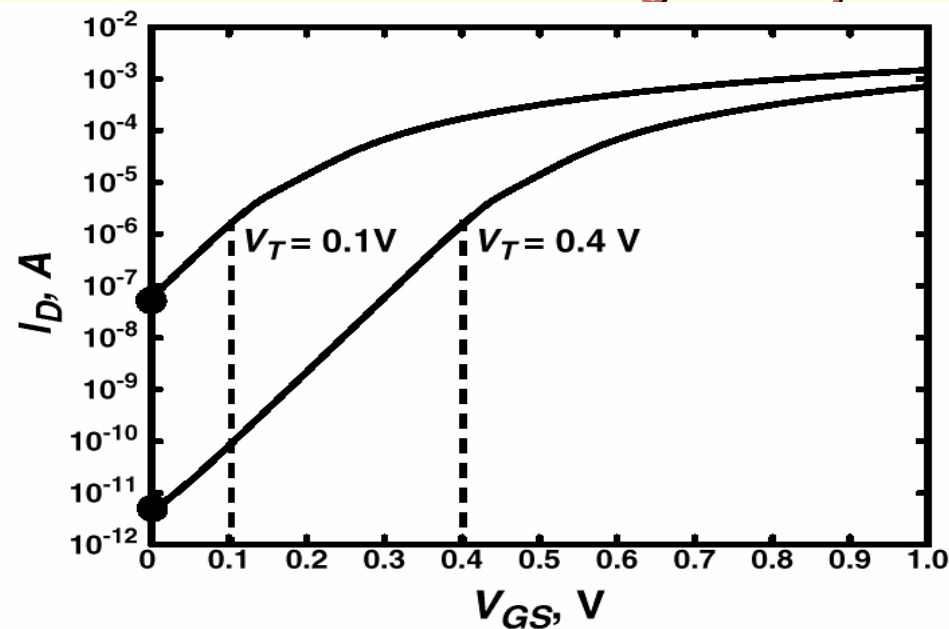


Input at 0

# Power, energy, and energy delay – 12

## Leakage → static dissipation

### *Subthreshold Leakage Component*



- Leakage control is critical for low-voltage operation

In our simplified model, currents for  $V_{GS}$  below  $V_T$  were assumed to be zero. However, subthreshold current is very important, especially for advanced technologies (low  $V_T$ 's) and can be the major component of power dissipation.



# Power, energy, and energy delay – 13

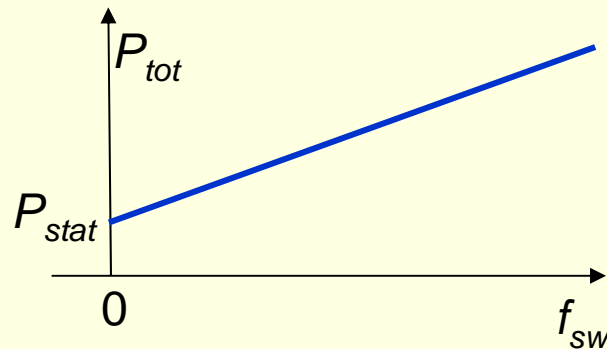
## Leakage → static dissipation

*Static power is due to the current that flows between supply rails in the absence of switching activity*  $P_{stat} = I_{stat} V_{DD}$

$$P_{tot} = P_{stat} + P_{dyn}$$

*Diode leakage +  
subthreshold current*

*Charge/discharge  $C_s$  +  
short-circuit current*



# Power, energy, and energy delay – 14

**Power-Delay Product (PDP)** = Average energy consumed per switching event (0→1 or 1→0)

$$PDP = \frac{CV_{DD}^2}{2}$$

**Energy-Delay Product (EDP)** = quality metric of gate =  $E \times t_p$

$$EDP = PDP \cdot t_p = \frac{CV_{DD}^2}{2} t_p$$

